

**IN THE CLAIMS**

**Please amend the claims as follows:**

Claim 1 (Currently Amended): An optical disk comprising:

[[a]] two molded substrates molded by injection molding, bonded together, and  
having information marks transferred thereto[[, on which]]; and  
a recording film disposed between the molded substrates and capable of recording  
information only once by a laser beam having a wavelength of 600 nm or less is formed, and  
on and from which information can be recorded and reproduced, or on which a reflection film  
is formed so as to reproduce information from the optical disk,

wherein the bonded and molded substrates including the recording film have a  
magnitude of a birefringence ~~of the entire region of the optical disk~~ is  $\pm 85$  nm or less when  
measured by a double pass mode of measurement in reflection, when PRML signal  
processing is used to reproduce the information.

Claim 2 (Canceled).

Claim 3 (Currently Amended): An optical disk according to claim [[2]] 1, wherein  
the magnitude of the double refraction component of the optical disk is +75 nm or less when  
measured by the double pass.

Claims 4-6 (Canceled).

Claim 7 (Currently Amended): An optical disk comprising:

[[a]] two molded substrates molded by injection molding, bonded together, and  
having information marks transferred thereto[[, on which]]; and

a recording film disposed between the molded substrates and capable of recording and  
erasing information is formed, and on and from which information can be recorded and  
reproduced using a laser beam having a wavelength of 600 nm or less,

wherein the bonded and molded substrates including the recording film have a  
magnitude of a birefringence ~~of the entire region of the optical disk~~ is  $\pm 70$  nm or less when  
measured by a double pass mode of measurement in reflection, when PRML signal  
processing is used to reproduce the information.

Claim 8 (Canceled).

Claim 9 (Previously Presented): An optical disk according to claim 7, wherein the  
magnitude of a double refraction component of the optical disk is  $+55$  nm or less when  
measured by a double pass mode of measurement in reflection, when PRML signal  
processing is used to reproduce the information.

Claims 10-12 (Canceled).

Claim 13 (Currently Amended): An optical disk comprising:

[[a]] two molded substrates molded by injection molding, bonded together, and  
having information marks transferred thereto[[, on which]]; and

a recording film disposed between the molded substrates and capable of recording  
information only once by a laser beam having a wavelength of 600 nm or less is formed, and

on and from which information can be recorded and reproduced, or on which a reflection film having a track pitch of  $0.40\text{ }\mu\text{m}$  and a minimum mark length of  $0.204\text{ }\mu\text{m}$  being formed to have a thickness of  $0.6\text{ mm}$  so as to reproduce information from the optical disk,

wherein the bonded and molded substrates including the recording film have a magnitude of a birefringence ~~of the entire region of the optical disk~~ is  $\pm 60\text{ nm}$  or less when measured by a double pass mode of measurement in reflection.

Claim 14 (Currently Amended): An optical disk comprising:

[[a]] two molded substrates molded by injection molding, bonded together, and having information marks transferred thereto[[, on which]]; and

a recording film disposed between the molded substrates and capable of recording and erasing information is formed, and on and from which information can be recorded and reproduced using a laser beam having a wavelength of  $600\text{ nm}$  or less, the reflection film having a track pitch of  $0.34\text{ }\mu\text{m}$  and a minimum mark length of  $0.187\text{ }\mu\text{m}$  being formed to have a thickness of  $0.6\text{ mm}$  so as to reproduce information from the optical disk,

wherein the bonded and molded substrates including the recording film have a magnitude of a birefringence ~~of the entire region of the optical disk~~ is  $\pm 40\text{ nm}$  or less when measured by a double pass mode of measurement in reflection.